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Status and Full-Aperture Measurements of a Convex Asphere from the Four-Point Optical Profilometer

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Topics



- System overview
 - Overall architecture (hexapod)
 - Metrology
 - Full-aperture, or low frequency (operational)
 - Smoothness, or mid frequency (under development)
 - Micro-roughness, or high freq (under development)
 - Polishing
- Capabilities
- Assembly and first-light test results
 - Full-aperture metrology
 - Polishing removal profile
- Future plans

Overall architecture: An integrated, in situ approach



A hexapod structure moves a "platter" in
 The platter all degrees of freedom over the substrate

The platter integrates *all* metrology and polishing functions

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Low frequency metrology: The 3 basic principles of 4-point profilometry...



If a rotating platter axis intersects the optic center of curvature, then a probe on the platter nominally sees no change in standoff (convex or concave substrate!)
 If four or more probes are on a platter, then there is *some* linear combination of their readings that

 \bullet (1) is insensitive to *all* rigid body motions

♦ (2) tells *something* about the shape of the test piece
A continuous measurement of this linear combination as the platter rotates yields a circular "hoop" profile

If one measures multiple "hoops" around a test piece, with each overlapping at least two others, then it is possible to "stitch" the profiles to obtain the total surface height map.

3 principles of 4-point profilometry...



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Summary of advantages



- Equally able to test concave and convex optics
- Completely self referencing
- Insensitive to rigid body motions of the test piece during measurements
- (Specially developed laser gauge probes provide absolutely reliable scale factor and mm-class range)
- By replacing the laser gauge probes with coarse probes (touch probes or non-contact alternatives), the instrument can measure optics in their ground state. Thus, one metrology instrument can take an optic from generation through final polish.

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Mid frequency metrology (to be implemented)



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Optical measurement of curvature profile, based on Bauer's Model 100 Profilometer

- Probe is placed on same "probe circle" as the 4point sensor probes
- Accuracy ~ 1-2 Angstroms over 25 mm

High frequency metrology (to be implemented)

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Micro-roughness
is characterized
with Total
Integrated
Scatter (TIS)

Probe is placed on the same
"probe circle" as the others

 Sensitivity ~ 1 Angstrom

Top: Inside of lid

Polishing





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 Baseline approach is Fluid Jet Polishing (FJP)

- FJP apparatus is
 incorporated on a
 bottom "lid" under
 the platter, thereby
 using the *same*hexapod
 infrastructure as the
 metrology
- This is key to our integrated, in situ approach

Bottom: Outside of lid (guard removed)

Capabilities



- Maximum diameter of mirror with mount: 2.0 meters
- Range of testable "speeds": f-0.7 concave to f-0.7 convex
- Maximum testable diameter:
 - ◆ 1.3 meters over full f-0.7 range
 - ◆ 1.5 meters for much slower "speeds"
- Testing time: ~1 minute per "hoop" (50-200 hoops typical)

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Predicted ultimate performance

Predicted rms figure measurement errors using various parent f#'s, |K|=1 (parabola), and vertex displ = 0.0 m •Assumptions: •K=-1 (parabola) 30.0 •On-axis 25.0 •F-numbers examined: 20.0 - 0.7 RMS (nm) •F-5 to F-0.7 15.0 2 3 - 5 •Diameters examined: 10.0 •Zero to 2.5 meters 5.0 •Current machine is 1.3 meters 0.0 0.5 0 1.5 2 2.5 Test piece diameter (m)

Assembly...





Assembly...







First-light test article



Convex
Uncoated
f-2.3
43-cm diameter

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Many isolated surface defects

Scanning demonstration





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Three independent, centered hoops to show repeatability (~1.6 nm rms) (note the 3 humps, ~0.1 micron – they agree well with FEA of self weight) Superposition of fourth hoop, taken after *rotating* test piece by 68.2 degrees

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Result of telling *software* to *derotate* fourth scan by 68.2 degrees

 Repeatability essentially unaffected

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- Full-surface scan (200 hoops stitched together)
- Pointillated views of the discrete hoop data points
- Plots differ only in vertical scale
- Note the three humps from self-weight deflection

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Another 200-hoop scan of the same piece, tipped by 3 degrees to demonstrate that the gravity direction does not induce a systematic measurement error

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Demonstration of the software's ability to interpolate the stitched data onto a rectangular grid

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Polishing wear profile

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- The first Fluid Jet Polishing (FJP) trials gave a very smooth, symmetric, Gaussian-like wear profile
- Full-width half max (FWHM) of 6 mm closely matched the jet size, which is easily variable
- There was no noticeable increase in roughness after three waves of removal
- Process parameters need optimizing, but this first result shows promise

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Future plans



Continue validation analyses on current test article

- Obtain and test a larger convex test article, with a pedigree, for comparison
- Implement mid frequency / high frequency metrology head
- Continue polishing implementation